

Attorney Docket No. SEL 246

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Application of:

Koichiro TANAKA

Serial No: 09/812,529

Filed: March 20, 2001

Art Unit: 2812

Examiner: Richard A. Booth

For: METHOD OF MANUFACTURING A
SEMICONDUCTOR DEVICE

) I hereby certify that this correspondence
) is being deposited with the United States
) Postal Service as first class mail in an
) envelope addressed to:
) Commissioner for Patents, P.O. Box 1450,
) Alexandria, VA 22313-1450, on August 12, 2004

) CHRISTINE A. BARGLIK
) Christine A. Barglik
)
)
) Date: August 12, 2004

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

Pursuant to 37 C.F.R. §1.97, as revised on February 4, 1992, 1135 OG 23-24, Applicant hereby calls the Examiner's attention to documents listed on the attached form, which documents may be material to the examination of this application. Copies of the references are enclosed herewith for the Examiner's consideration.

The family of JP 04-242724 cited herein includes:

US Patent no. 5,453,858
US Patent no. 5,514,879
US Patent no. 5,614,732
US Patent no. 5,701,167
US Patent no. 5,849,601
US Patent no. 5,859,445
US Patent no. 6,023,075

The family of JP 07-307304 cited herein includes:
US Patent no. 6,096,581
US Patent no. 6,509,212

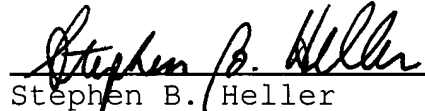
No inference should be drawn that the attached list sets forth a comprehensive investigation of the prior art, that any or all are pertinent to the invention, or that any apparatus disclosed is equivalent to the subject invention.

The citation of the above-discussed documents is not to be construed as an assertion that more pertinent art could not possibly be in existence. Citation of any document herein is not to be construed as an admission that any subject matter disclosed in the document is necessarily within the inventive field of endeavor, that any disclosure is necessarily prior in time to a particular date which may be relevant to the instant patent application, and/or that any disclosure is otherwise necessarily prior art with respect to the instant invention.

Applicant also respectfully reserves the right to later set forth how the instant invention is distinguished over the disclosure of any document or other art, including the disclosure of those documents discussed herein, that may be cited by the Examiner in rejecting a claim in the instant patent application.

As an RCE is being filed herewith, no fee is believed necessary. However, if any such fee is required, please charge our Deposit Account No. 50/1039.

Respectfully submitted,



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Registration No: 30,181

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LIST OF PUBLICATIONS CITED BY APPLICANT			<u>Atty. Docket No.</u> SEL 246	<u>Serial No.</u> 09/812,529		
			<u>Applicant</u> Koichiro TANAKA			
			<u>Filing Date</u> March 20, 2001	<u>Group</u> 2812		
U.S. PATENT DOCUMENTS						
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	4,330,363	05/18/82	Biegesen et al	156	620	08/28/80
	4,466,179	08/21/84	Kasten	29	576	10/19/82
	4,915,772	04/10/90	Fehlner et al	156	620	10/01/86
	5,145,808	09/08/92	Sameshima et al	437	173	08/20/91
	5,194,853	03/16/93	Asada	340	784	12/19/91
	5,247,375	09/21/93	Mochizuki et al	359	54	12/08/92
	5,264,383	11/23/93	Young	437	40	06/23/92
	5,365,875	11/22/94	Asai et al	117	7	09/18/92
	5,372,836	12/13/94	Imahashi et al	427	8	03/26/93
	5,403,762	04/04/95	Takemura	437	40	06/28/94
	5,403,772	04/04/95	Zhang et al	437	101	12/03/93
	5,413,958	05/09/95	Imahashi et al	437	173	11/16/93
	5,414,442	05/09/95	Yamazaki et al	345	89	06/12/92
	5,432,122	07/11/95	Chae	437	101	11/03/93
	5,449,637	09/12/95	Saito et al	437	57	09/27/93
	5,453,858	09/26/95	Yamazaki	359	59	02/03/95
	5,477,073	12/19/95	Wakai et al	257	347	08/09/94
	5,514,879	05/07/96	Yamazaki	257	65	06/07/95
	5,529,630	06/25/96	Imahashi et al	118	665	02/09/95
	5,529,937	06/25/96	Zhang et al	437	10	07/20/94
	5,561,081	10/01/96	Takenouchi et al	437	174	02/03/94
	5,563,426	10/08/96	Zhang et al	257	66	11/18/94
	5,565,377	10/15/96	Weiner et al	437	173	10/27/94
	5,570,105	10/29/96	Koyama	345	98	12/21/94
	5,614,732	03/25/97	Yamazaki	257	66	08/19/94
	5,680,147	10/21/97	Yamazaki et al	345	94	05/19/92
	5,701,167	12/23/97	Yamazaki	349	42	09/13/96
	5,708,252	01/13/98	Shinohara et al	219	121.73	01/22/96
	5,767,930	06/16/98	Kobayashi et al	349	42	05/20/97
	5,849,601	12/15/98	Yamazaki	437	101	04/22/94
	5,858,473	01/12/99	Yamazaki et al	427	554	09/06/96
	5,859,445	01/12/99	Yamazaki	257	66	02/14/97
	5,897,799	04/27/99	Yamazaki et al	219	121.75	06/11/96
	5,939,731	08/17/99	Yamazaki et al	257	59	01/08/97
	5,943,593	08/24/99	Noguchi et al	438	487	05/22/98



FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	APPLICANT	English Abstract	English Trans.	FILING DATE
	JP 58-127318	07/29/83	Nippon Telegraph & Telephone Corp.	X		01/25/82
	JP 59-161014	09/11/84	Seiko Instrument & Electronics Ltd.	X		03/03/83
	EP 0 091 806	10/19/83	Fujitsu Ltd.			04/08/83
	JP 02-042717	02/13/90	Hitachi Ltd.	X		08/03/88
	JP 03-280531	12/11/91	Fuotonikusu KK	X		03/29/90
	JP 04-242724	08/31/92	Semiconductor Energy Lab Co. Ltd		X	12/25/90
	JP 04-282869	10/07/92	GTC KK	X		03/11/91
	JP 05-040278	02/19/93	NEC Corp.	X		08/06/91
	JP 05-175235	07/13/93	Sharp Corp.	X		12/25/91
	JP 05-203977	08/13/93	Seiko Epson Corp.	X		08/28/92
	JP 05-211167	08/20/93	NEC Corp.	X		11/29/91
	JP 05-251342	09/28/93	Semiconductor Energy Lab Co. Ltd	X		12/04/92
	JP 06-045272	02/18/94	Hitachi Ltd.	X		07/21/92
	JP 06-059278	03/04/94	Hitachi Ltd.	X		08/07/92
	JP 06-260502	09/16/94	Seiko Epson Corp.	X		03/04/93
	JP 07-307304	11/21/95	Semiconductor Energy Lab Co. Ltd	X		05/13/94

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS

(Include name of author (in CAPITAL LETTERS), title of article or item (book, magazine, journal, serial, symposium, catalog, etc.) date, pages(s), volume-issue number(s), publisher, city and/or country where published).

- 1) FUJIEDA, I. et al, "Self-Referenced Poly-Si TFT Amplifier Readout for a Linear Image Sensor," IDEM 93, pp. 587-590, (1993).
- 2) BONNEL, M. et al, "Polycrystalline Silicon Thin-Film Transistors with Two-Step Annealing Process," IEEE Electron Device Letters, vol. 14, no. 12, pp. 551-553, December, (1993).
- 3) FUSE, M. et al, "Performance of Poly-Si Thin Film Transistors Fabricated by Excimer-Laser Annealing of SiH_4^- and Si_2H_6^- Source Low Pressure Vapor Deposited a-Si Films With or Without Solid-Phase Crystallization," Solid State Phenomena, vols. 37-38, pp. 565-570 (1994).
- 4) Webster's II New Riverside University Dictionary, (1994).

EXAMINER:

DATE CONSIDERED:

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP form. Draw line through citation if not in conformance and not considered. Include a copy of this form with the next communication to applicant.



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	5,968,383	10/19/99	Yamazaki et al	219	121.75	10/23/97
	6,002,101	12/14/99	Yamazaki et al	219	121.75	10/23/97
	6,011,277	01/04/00	Yamazaki	257	66	09/09/98
	6,023,075	02/08/00	Yamazaki	257	72	10/31/97
	6,066,516	05/23/00	Miyasaka	438	149	01/31/97
	6,096,581	08/01/00	Zhang et al	438	149	05/02/96
	6,159,777	12/12/00	Takenouchi et al	438	149	10/28/97
	6,261,856 B1	07/17/01	Shinohara et al	438	30	12/10/98
	6,509,212 B1	01/21/03	Zhang et al	438	149	01/26/99
	6,528,397 B1	03/04/03	Taketomi et al	438	487	06/16/00
	6,723,590 B1	04/20/04	Zhang et al	438	166	07/13/00

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(Include name of author (in CAPITAL LETTERS), title of article or item (book, magazine, journal, serial, symposium, catalog, etc.) date, pages(s), volume-issue number(s), publisher, city and/or country where published).

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